

# C3M0015065K

Silicon Carbide Power MOSFET

C3M™ MOSFET Technology

N-Channel Enhancement Mode

## Features

- C3M™ SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery ( $Q_{rr}$ )
- Halogen free, RoHS compliant

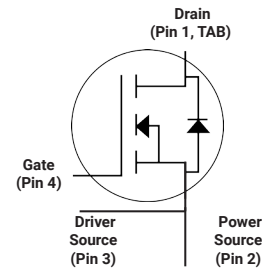
## Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## Applications

- EV chargers
- Solar inverters
- UPS
- SMPS
- DC/DC converters

## Package



Part Number	Package	Marking
C3M0015065K	TO 247-4	C3M0015065K

## Maximum Ratings ( $T_c=25^\circ\text{C}$ , unless otherwise specified)

Symbol	Parameter	Value	Unit	Note
$V_{DSmax}$	Drain - Source Voltage	650	V	
$V_{GSmax}$	Gate - Source voltage	-8/+19	V	Note 1
$I_D$	Continuous Drain Current, $V_{GS} = 15\text{ V}$ , $T_c = 25^\circ\text{C}$	120	A	Fig. 19 Note 2
	Continuous Drain Current, $V_{GS} = 15\text{ V}$ , $T_c = 100^\circ\text{C}$	96		
$I_{D(pulse)}$	Pulsed Drain Current, Pulse width $t_p$ limited by $T_{jmax}$	418	A	
$P_D$	Power Dissipation, $T_c=25^\circ\text{C}$ , $T_j = 175^\circ\text{C}$	416	W	Fig. 20
$T_J, T_{stg}$	Operating Junction and Storage Temperature	-40 to +175	$^\circ\text{C}$	
$T_L$	Solder Temperature, 1.6mm (0.063") from case for 10s	260	$^\circ\text{C}$	
$M_d$	Mounting Torque, (M3 or 6-32 screw)	1	Nm	
		8.8	lbf-in	

Note (1): Recommended turn off / turn on gate voltage  $V_{GS} = -4V \dots 0V / +15V$

Note (2): Package limited to 120 A

Electrical Characteristics ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	650			V	$V_{GS} = 0\text{ V}, I_D = 100\text{ }\mu\text{A}$	
$V_{GS(th)}$	Gate Threshold Voltage	1.8	2.3	3.6	V	$V_{DS} = V_{GS}, I_D = 15.5\text{ mA}$	Fig. 11
			1.9		V	$V_{DS} = V_{GS}, I_D = 15.5\text{ mA}, T_J = 175^\circ\text{C}$	
$I_{DSS}$	Zero Gate Voltage Drain Current		1	50	$\mu\text{A}$	$V_{DS} = 650\text{ V}, V_{GS} = 0\text{ V}$	
$I_{GSS}$	Gate-Source Leakage Current		10	250	nA	$V_{GS} = 15\text{ V}, V_{DS} = 0\text{ V}$	
$R_{DS(on)}$	Drain-Source On-State Resistance	10.5	15	21	m $\Omega$	$V_{GS} = 15\text{ V}, I_D = 55.8\text{ A}$	Fig. 4, 5, 6
			20			$V_{GS} = 15\text{ V}, I_D = 55.8\text{ A}, T_J = 175^\circ\text{C}$	
$g_{fs}$	Transconductance		42		S	$V_{DS} = 20\text{ V}, I_{DS} = 55.8\text{ A}$	Fig. 7
			40			$V_{DS} = 20\text{ V}, I_{DS} = 55.8\text{ A}, T_J = 175^\circ\text{C}$	
$C_{iss}$	Input Capacitance		5011		pF	$V_{GS} = 0\text{ V}, V_{DS} = 400\text{ V}$ $f = 100\text{ KHz}$ $V_{AC} = 25\text{ mV}$	Fig. 17, 18
$C_{oss}$	Output Capacitance		289				
$C_{rss}$	Reverse Transfer Capacitance		31				
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		357				Note: 3
$C_{o(tr)}$	Effective Output Capacitance (Time Related)		516				Note: 3
$E_{oss}$	$C_{oss}$ Stored Energy		29		$\mu\text{J}$		Fig. 16
$E_{ON}$	Turn-On Switching Energy (Body Diode)		401		$\mu\text{J}$	$V_{DS} = 400\text{ V}, V_{GS} = -4\text{ V}/15\text{ V}, I_D = 55.8\text{ A},$ $R_{G(ext)} = 5\text{ }\Omega, L = 57.6\text{ }\mu\text{H}, T_J = 175^\circ\text{C}$ FWD = Internal Body Diode of MOSFET	Fig. 25
$E_{OFF}$	Turn Off Switching Energy (Body Diode)		254				
$E_{ON}$	Turn-On Switching Energy (External Diode)		234		$\mu\text{J}$	$V_{DS} = 400\text{ V}, V_{GS} = -4\text{ V}/15\text{ V}, I_D = 55.8\text{ A},$ $R_{G(ext)} = 5\text{ }\Omega, L = 57.6\text{ }\mu\text{H}, T_J = 175^\circ\text{C}$ FWD = External SiC DIODE	Fig. 25
$E_{OFF}$	Turn Off Switching Energy (External Diode)		303				
$t_{d(on)}$	Turn-On Delay Time		23		ns	$V_{DD} = 400\text{ V}, V_{GS} = -4\text{ V}/15\text{ V}$ $I_D = 55.8\text{ A}, R_{G(ext)} = 5\text{ }\Omega, L = 57.6\text{ }\mu\text{H}$ Timing relative to $V_{DS}$ Inductive load	Fig. 26
$t_r$	Rise Time		32				
$t_{d(off)}$	Turn-Off Delay Time		57				
$t_f$	Fall Time		15				
$R_{G(int)}$	Internal Gate Resistance		1.5		$\Omega$	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$	
$Q_{gs}$	Gate to Source Charge		53		nC	$V_{DS} = 400\text{ V}, V_{GS} = -4\text{ V}/15\text{ V}$ $I_D = 55.8\text{ A}$ Per IEC60747-8-4 pg 21	Fig. 12
$Q_{gd}$	Gate to Drain Charge		58				
$Q_g$	Total Gate Charge		188				

Note (3):  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V  
 $C_{o(tr)}$ , a lumped capacitance that gives same charging time as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V

Reverse Diode Characteristics ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	4.7		V	$V_{GS} = -4\text{ V}, I_{SD} = 27.9\text{ A}, T_j = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.2		V	$V_{GS} = -4\text{ V}, I_{SD} = 27.9\text{ A}, T_j = 175^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		79	A	$V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$	
$I_{S, \text{pulse}}$	Diode pulse Current		223	A	$V_{GS} = -4\text{ V}$ , pulse width $t_p$ limited by $T_{jmax}$	
$t_{rr}$	Reverse Recover time	22		ns	$V_{GS} = -4\text{ V}, I_{SD} = 55.8\text{ A}, V_R = 400\text{ V}$ $\text{dif}/\text{dt} = 4000\text{ A}/\mu\text{s}, T_j = 175^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	510		nC		
$I_{rrm}$	Peak Reverse Recovery Current	39		A		
$t_{rr}$	Reverse Recover time	26		ns	$V_{GS} = -4\text{ V}, I_{SD} = 55.8\text{ A}, V_R = 400\text{ V}$ $\text{dif}/\text{dt} = 2500\text{ A}/\mu\text{s}, T_j = 175^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	432		nC		
$I_{rrm}$	Peak Reverse Recovery Current	28		A		

## Thermal Characteristics

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.35	$^\circ\text{C}/\text{W}$		Fig. 21
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40			

## Typical Performance

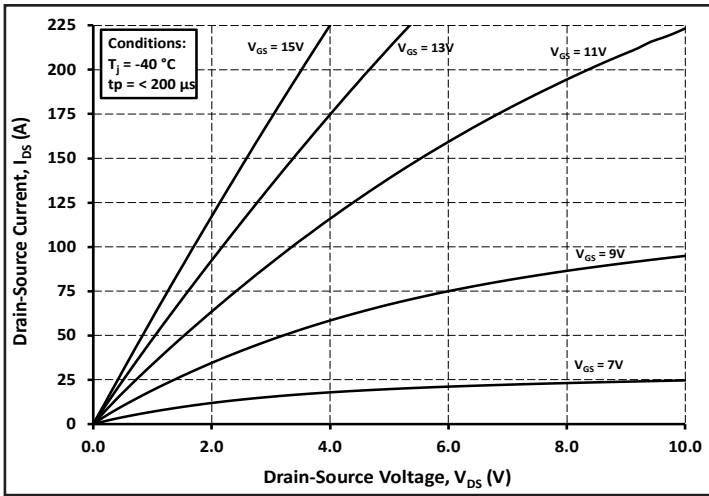
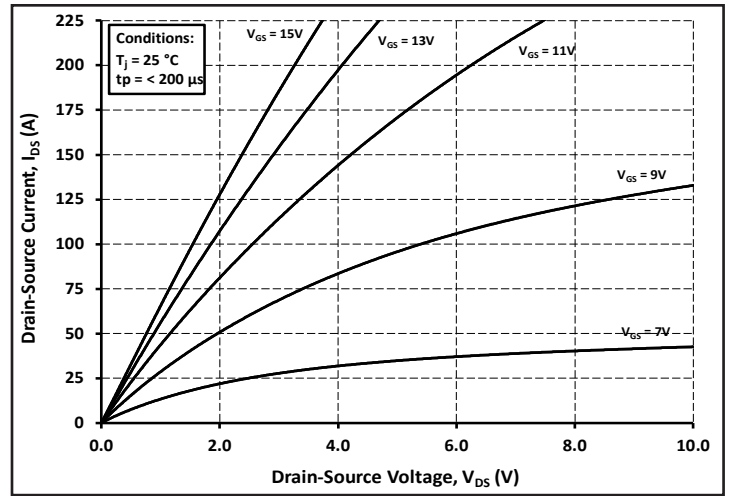
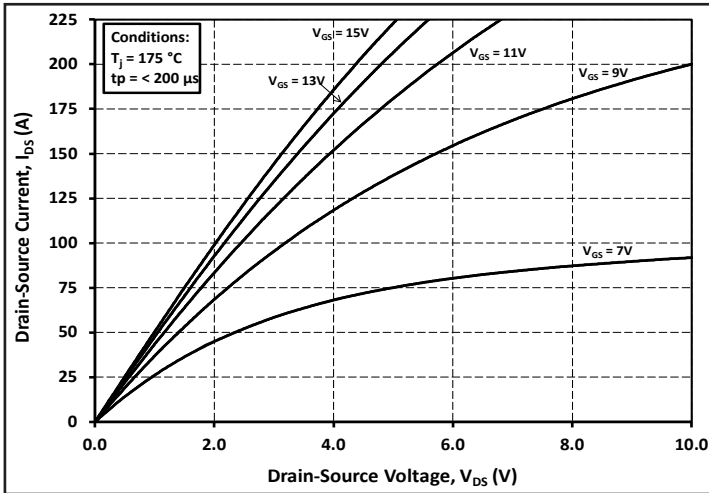
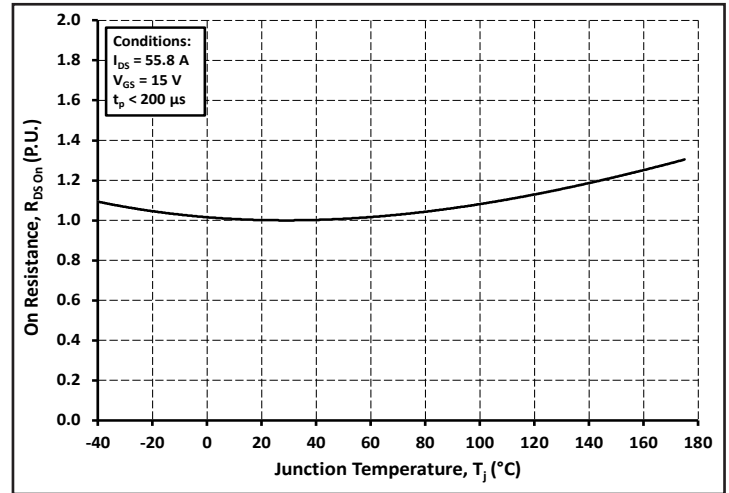
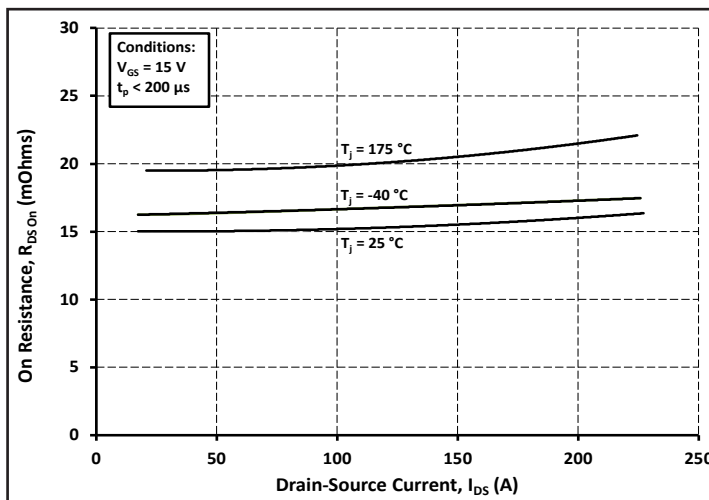
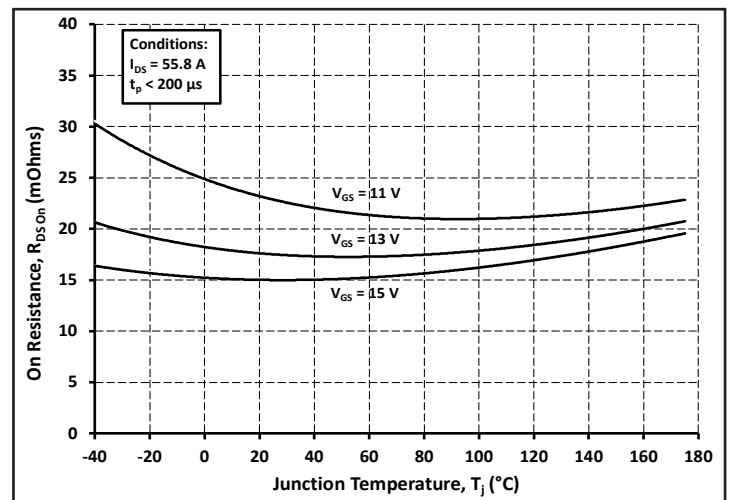
Figure 1. Output Characteristics  $T_j = -40\text{ }^{\circ}\text{C}$ Figure 2. Output Characteristics  $T_j = 25\text{ }^{\circ}\text{C}$ Figure 3. Output Characteristics  $T_j = 175\text{ }^{\circ}\text{C}$ 

Figure 4. Normalized On-Resistance vs. Temperature

Figure 5. On-Resistance vs. Drain Current  
For Various TemperaturesFigure 6. On-Resistance vs. Temperature  
For Various Gate Voltage

## Typical Performance

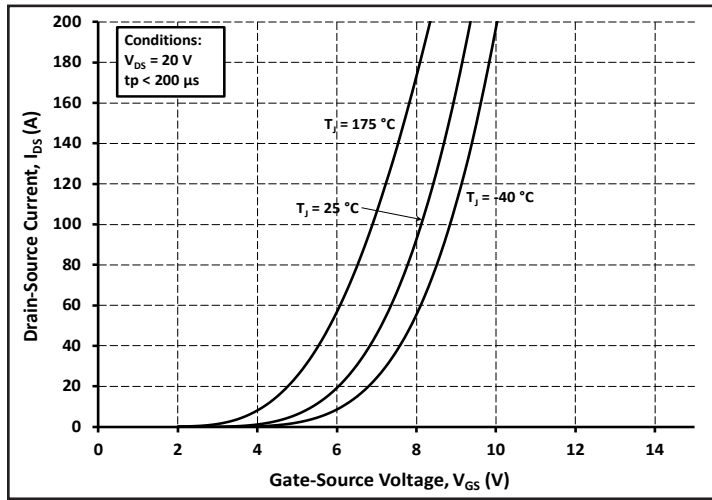


Figure 7. Transfer Characteristic for Various Junction Temperatures

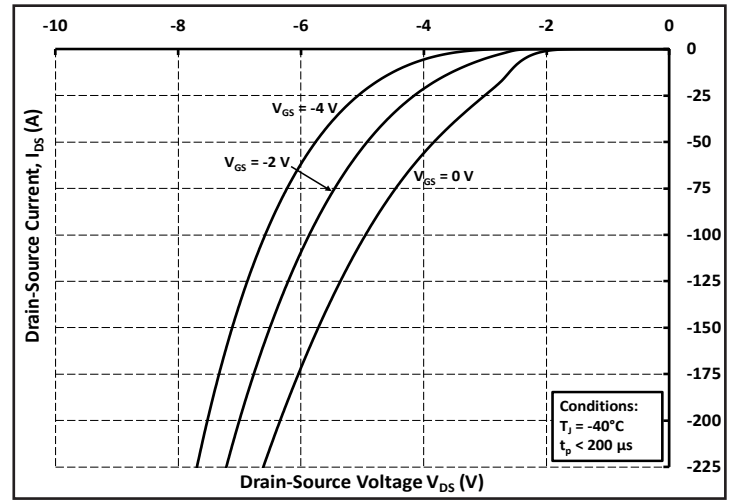


Figure 8. Body Diode Characteristic at -40 °C

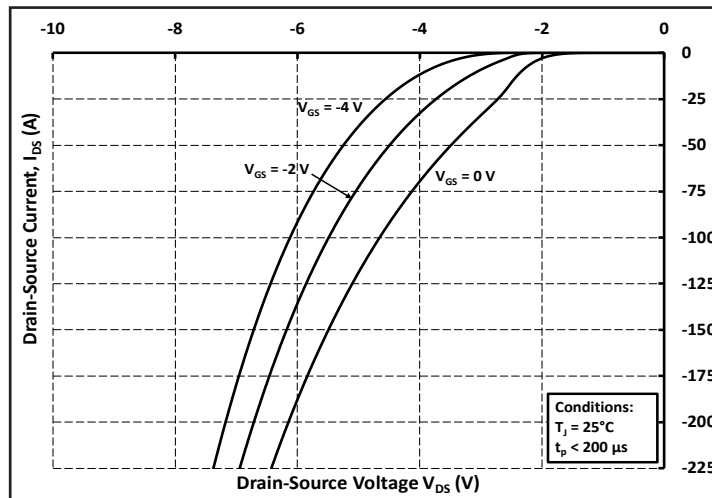


Figure 9. Body Diode Characteristic at 25 °C

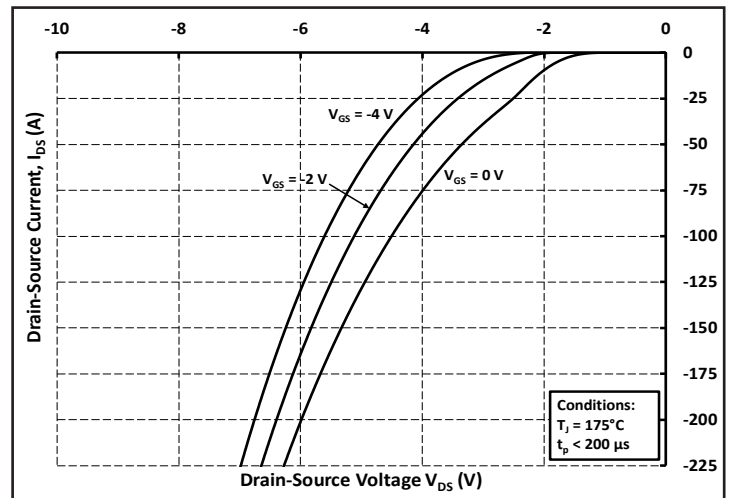


Figure 10. Body Diode Characteristic at 175 °C

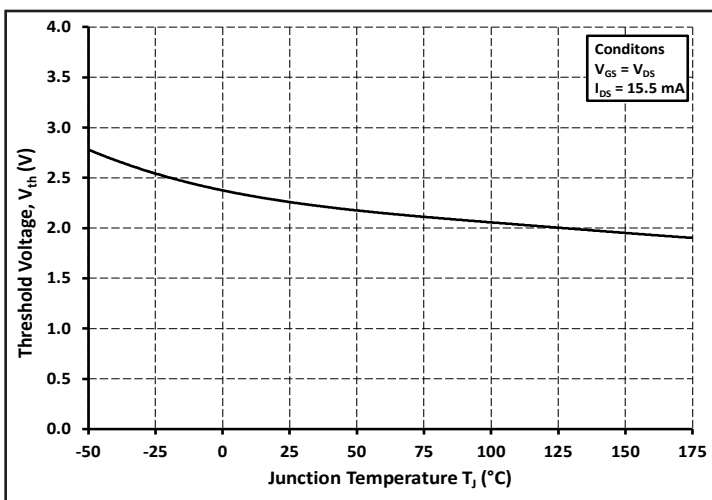


Figure 11. Threshold Voltage vs. Temperature

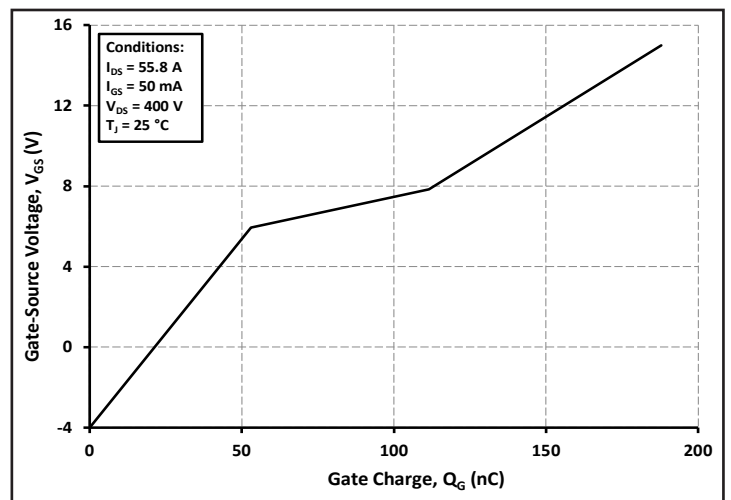


Figure 12. Gate Charge Characteristics

## Typical Performance

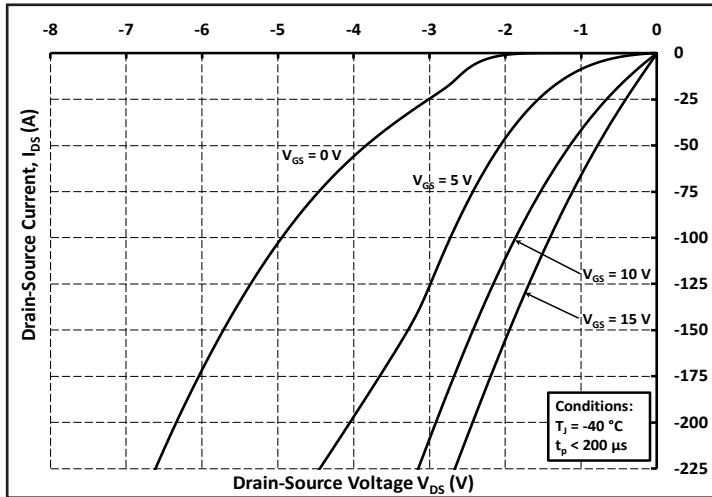


Figure 13. 3rd Quadrant Characteristic at -40 °C

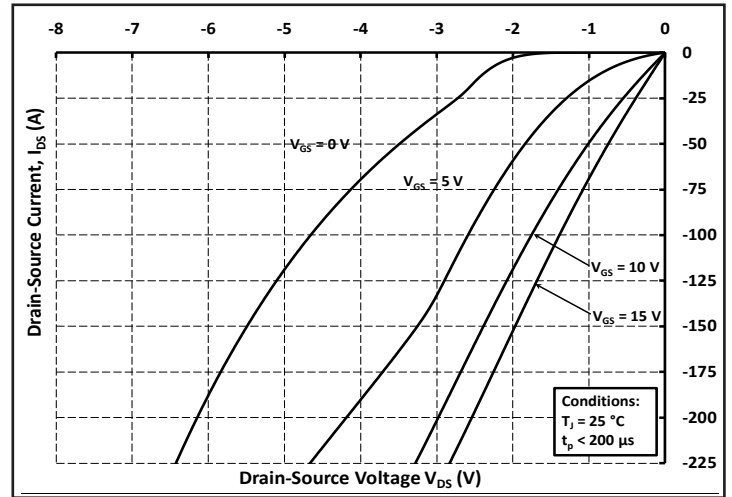


Figure 14. 3rd Quadrant Characteristic at 25 °C

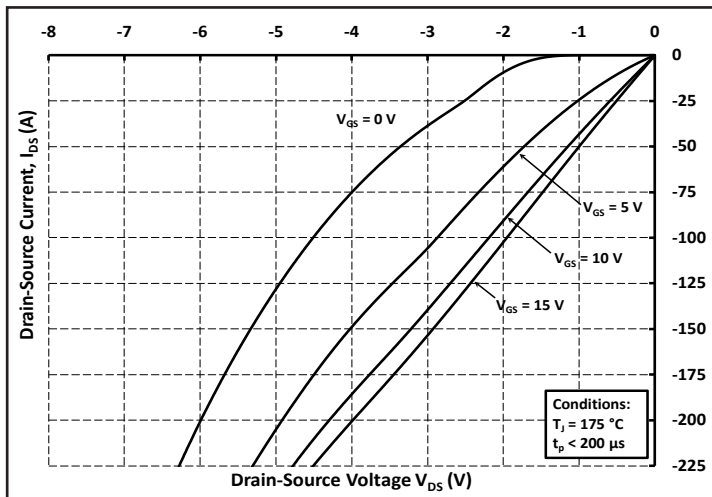


Figure 15. 3rd Quadrant Characteristic at 175 °C

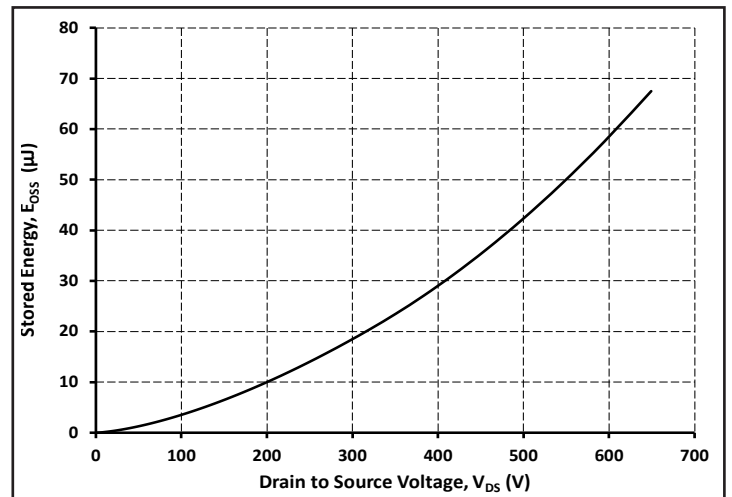


Figure 16. Output Capacitor Stored Energy

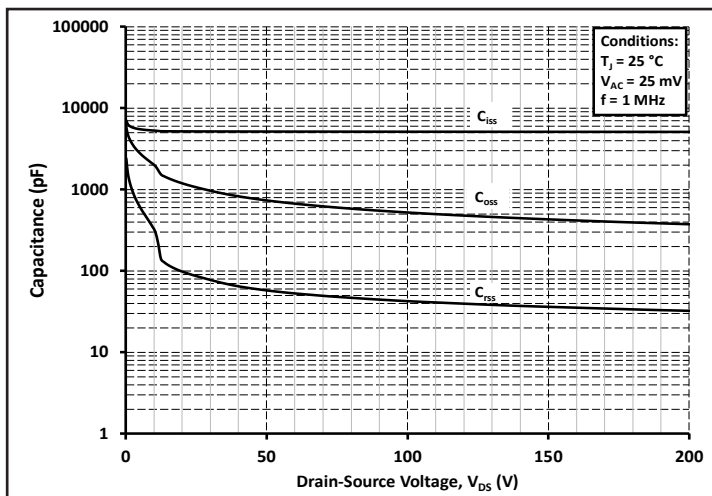


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

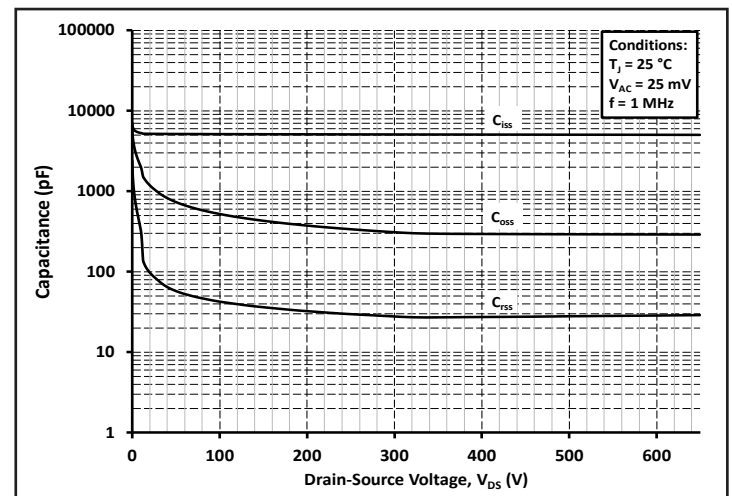


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)

## Typical Performance

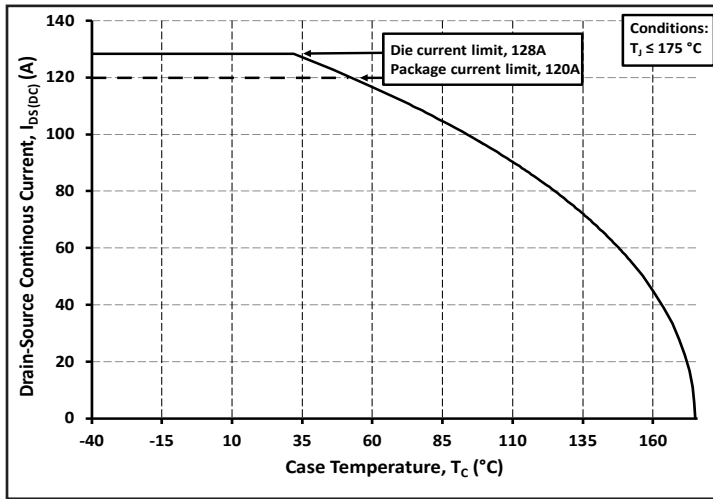


Figure 19. Continuous Drain Current Derating vs. Case Temperature

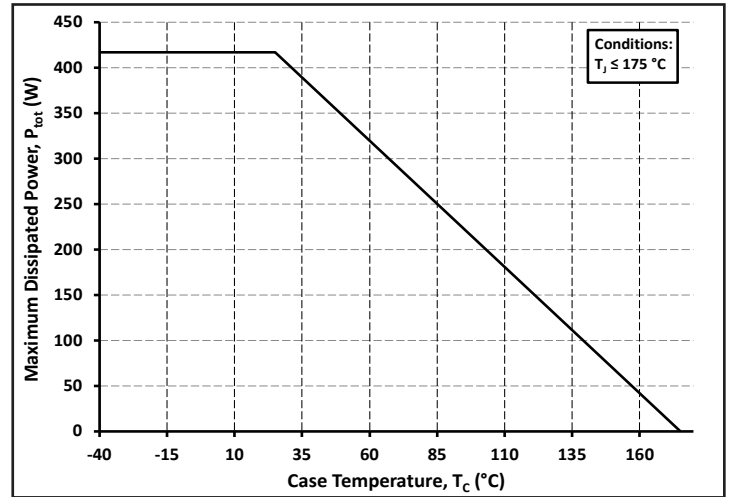


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

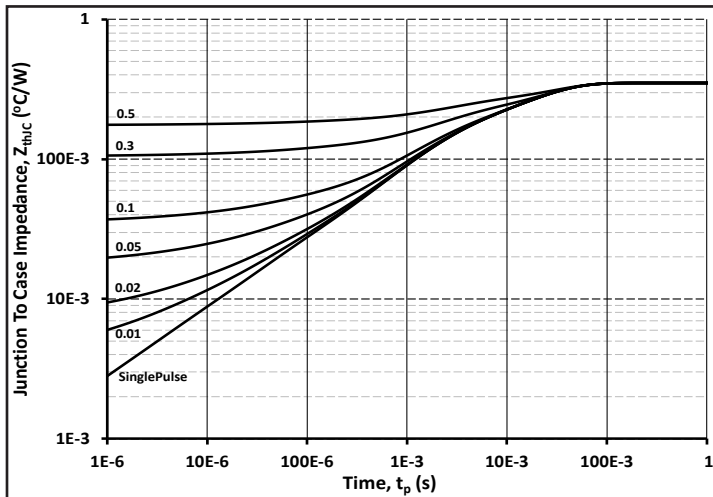


Figure 21. Transient Thermal Impedance (Junction - Case)

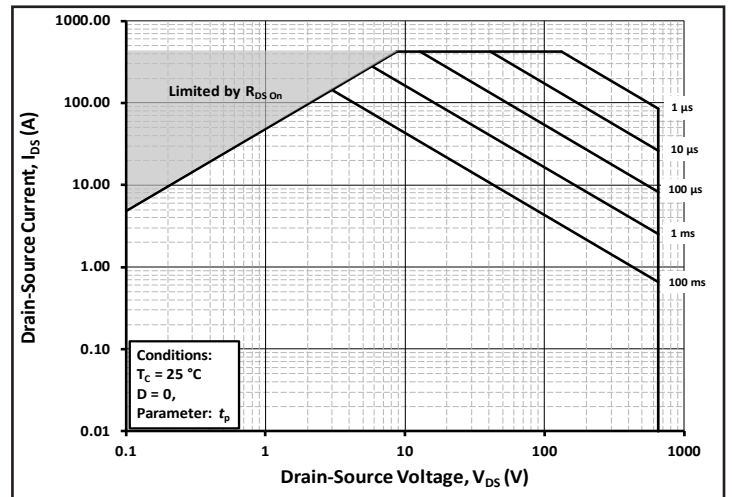
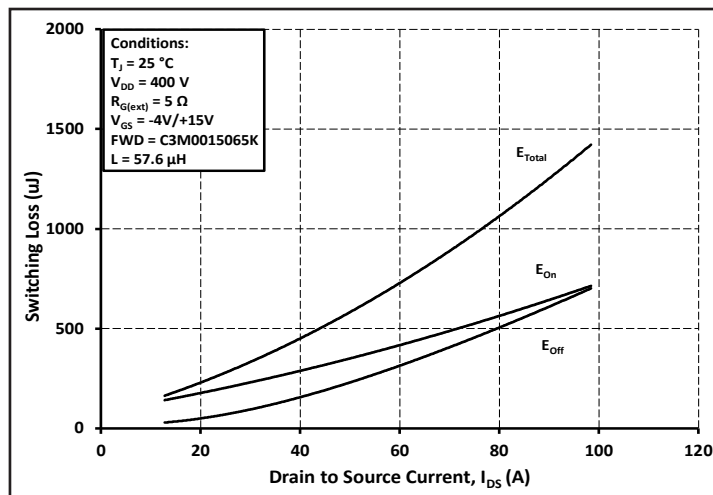
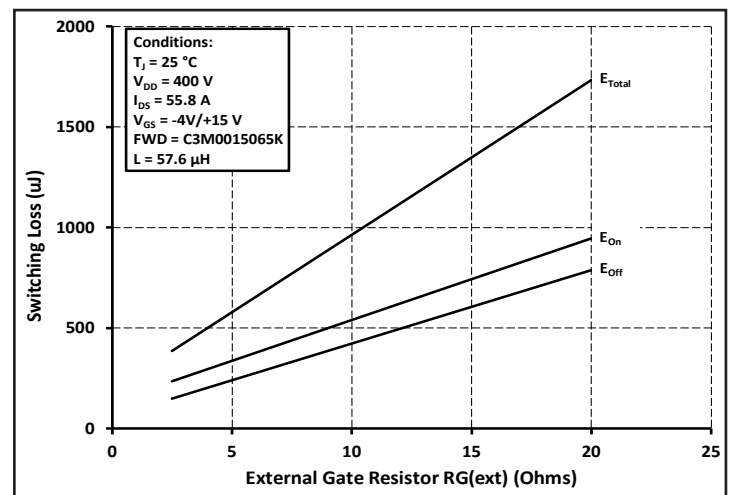


Figure 22. Safe Operating Area

Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 400V$ )Figure 24. Clamped Inductive Switching Energy vs.  $R_{G(ext)}$



Typical Performance

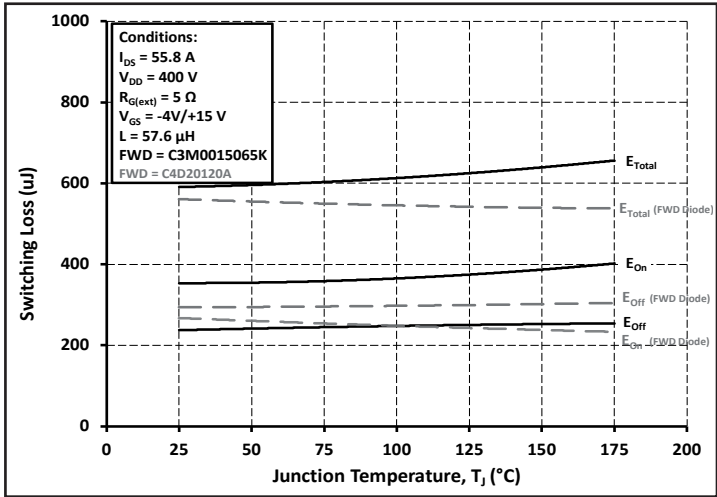


Figure 25. Clamped Inductive Switching Energy vs. Temperature

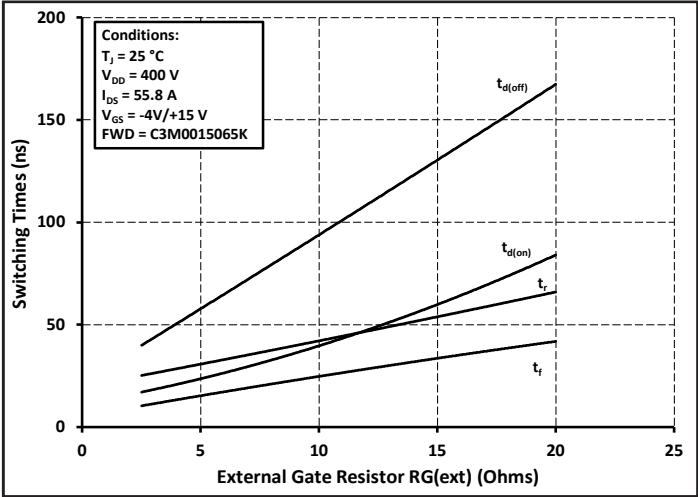


Figure 26. Switching Times vs.  $R_{G(ext)}$





Test Circuit Schematic

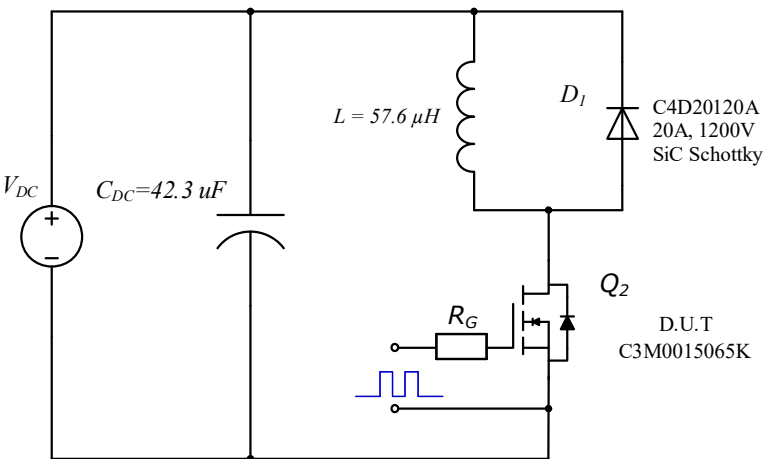


Figure 27. Clamped Inductive Switching Waveform Test Circuit

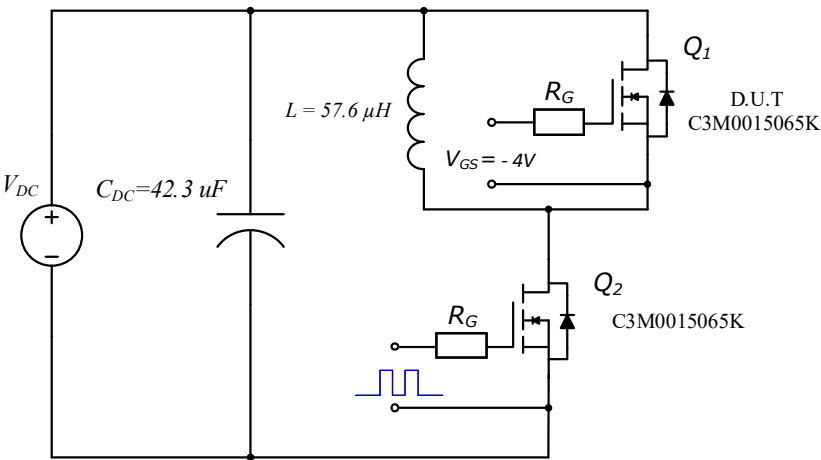


Figure 28. Body Diode Recovery Test Circuit



## Package Dimensions

TO-247-4L

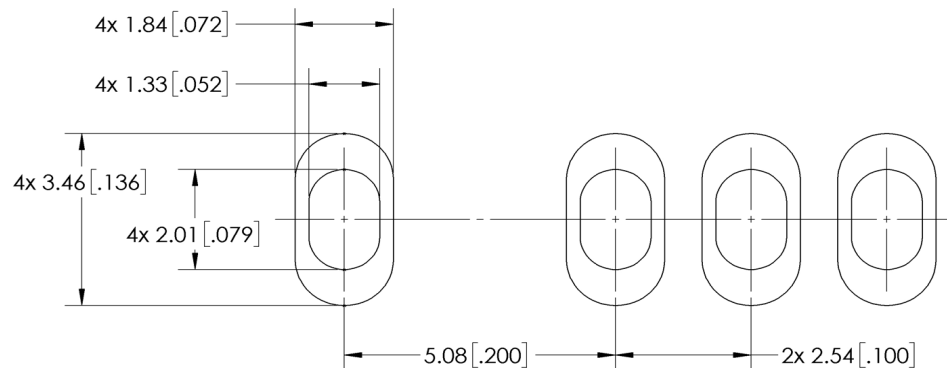
NOTE ;

1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT .
2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
3. ALL DIMENSIONS ARE IN MILLIMETERS.  
ANGLES ARE IN DEGREES.
4. 'N' IS THE NUMBER OF TERMINAL POSITIONS.
5. DIMENSION DO NOT INCLUDE BURR OR MOLD FLASH.

SYM	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
b7	1.30	1.70
b8	1.80	2.20

c'	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
N*	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
øP	3.51	3.65
Q	5.49	6.00
S	6.04	6.30
T	17.5° REF.	
W	3.5° REF.	
X	4° REF.	

## Recommended Solder Pad Layout





## Notes

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